1. Type of Change (Major or Minor)

Major

2. Change Description

Changed from:

1. Temperature cycling and radiography steps performed on all grades.

Changed To:

1. Temperature cycling and radiography steps will now be performed only on A-grade material

3. Impact on Product and/or Process

Simplified inline screening and lot acceptance flow.

4. Justification for Change

Alignment with MIL-PRF-38535 sampling requirements on A-grade material.

5. Change Risk Assessment

Low. A-grade material is still available with x-ray and temperature cycling steps in place.

6. Qualification Plan

N/A

7. Qualification Report

N/A

8. Summary

See change description.

9. Impacted Device - Document - Process List

All Apogee Semiconductor B-grade, C-grade, and E-grade products.

10. Sample Availability Date and Projected Production Shipment

Sample availability date: N/A. Please contact Apogee Semiconductor for samples if needed.

Projected production shipment date: September 13th, 2025 or upon PCN approval.

11. File Attachment

Changed from:

1. Inline screening flow: Apogee_Screening_Flow_A02.pdf
2. Lot qualification flow: Apogee_Lot_Acceptance_Flow_A05.pdf

Changed to:

1. Inline screening and lot qualification flows: Apogee_Semiconductor_Product_Grades_and_Quality_Flows_A00.pdf